

**Notice of References Cited**Application/Control No.  
09/802,975Applicant(s)/Patent Under  
Reexamination  
AHMED ET AL.Examiner  
James J. LeybourneArt Unit  
2881

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## NON-PATENT DOCUMENTS

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	U	"Nanoscale field emission structures for ultra-low voltage operation at atmospheric pressure", Driskill-Smith et al. Applied Physics Letters, volume 75, pp 2845-2847 (1999)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.